

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10642673	LIGHTSTONE ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Chawan, Sheela C	2624	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	103,106,107,151,173,181,190,199,224,232,236,254,275, 278	12/21/06	SCC
348	459,558,441,448,526,96,700,439.1,452,443,449,415.1,4 46,	12/21/06	SCC
375	240.12,240.15	12/21/06	SCC
386	111,131,129,	12/21/06	SCC
ABOVE SEARCH UP- DATE.		5/22/07	SCC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST, USPAT,US-PGPUB,EPO,JPO,DERWENT,IBM-TDB	12/21/06	SCC
INVENTOR NAME SEARCH.	12/21/06	SCC
SEARCH EAST AND OTHER DATA BASE , SEE ATTACHED SEARCH HISTORY.	5/22/07	SCC
382/100,103,106,107,173,181,232,236,239,254,275,278.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	"	"
348/459,458,441,448,526,96,700,439.1,452,443,449,415.1,446.CCLS. "	"	"
375/240.12,240.15.CCLS. "	"	"
386/111,131,129.CCLS. "	"	"
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	"	"
SEARCH IEEE OR INSPEC DATA BASE SEARCH.	"	"
ABOVE SEARCH UP-DATE.	"	"

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	181, 236,278	5/22/07	SCC
348	441,526	"	"